

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

EXPRESS MAIL NO. EV 326703367 US

Applicant : Tiow Seng Tan, et al.
Application No. : 10/566,858
Filed : January 31, 2006
Title : TRAPEZOIDAL SHADOW MAPS

Grp./Div. : 2245
Examiner : To be determined
Docket No. : 57090/C982

INFORMATION DISCLOSURE STATEMENT
37 CFR § 1.97(b)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450


Post Office Box 7068
Pasadena, CA 91109-7068
June 28, 2006

Commissioner:

In compliance with the duty of disclosure under 37 CFR §§ 1.56, 1.97 and 1.98, and in accordance with the provisions in the Manual of Patent Examining Procedure §§ 609 and 707.05(b), enclosed is FORM PTO/SB/08A/B listing the references that are known to applicant. Copies of each of the listed Foreign Patent and Other Documents are enclosed. This filing is timely because it is made during one of the periods described in 37 CFR § 1.97(b).

It is respectfully requested that the listed references be considered in the examination of this application and identified on the list of references cited on the patent issuing for this application. Applicant also requests that an initialed copy of FORM PTO/SB/08A/B be entered in the application file and returned to applicant with the next communication from the Office in accordance with MPEP § 609.

Respectfully submitted,
CHRISTIE, PARKER & HALE, LLP

By 
D. Bruce Prout
Reg. No. 20,958
626/795-9900

DBP/dg
Enclosures: Form PTO/SB/08A/B, w/references
DLG PAS688743.1-*06/27/06 10:06 AM

FORM PTO/SB/08A/B (10-01) Substitute for PTO-1449A/B	Attorney Docket Number	57090/C982
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)	Application Number	10/556,858
	Filing Date	January 31, 2006
	Applicant(s)	Tiow Seng Tan, et al.
	Group Art Unit	2245
	Examiner Name	To be determined

U.S. PATENT DOCUMENTS				
EXAMINER INITIALS	Cite No. ¹	DOCUMENT NUMBER Number - Kind Code ² (If Known)	Publication Date MM-DD-YYYY	Name of Patentee
		6,252,608 B1	06-26-2001	Snyder et al.
		6,437,782	08-20-2002	Pieragostini et al.
		2002/0018063 A1	02-14-2002	Donavan et al.
		2002/0067355 A1	06-06-2002	Randel

FOREIGN PATENT DOCUMENTS					
EXAMINER INITIALS	Cite No. ¹	FOREIGN PATENT DOCUMENT Country Code ³ - Number ⁴ - Kind Code ⁵ (If Known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T ⁶ (✓)
		EP 1 073 016 A1	01-31-2001	Sawa et al.	
		EP 1 126 415 A2	08-22-2001	Hino et al.	

OTHER DOCUMENTS		
EXAMINER INITIALS	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		Martin, T., et al., <i>Trapezoidal Shadow Maps</i> , April 7, 2003, pp 1-7
		Martin, T., et al., <i>Anti-aliasing and Continuity with Trapezoidal Shadow Maps</i> , School of Computing, National University of Singapore, 2004, pp 1-10
		Brabec, S., et al., <i>Practical Shadow Mapping</i> , Journal of Graphics Tools, 2003, pp 1-9
		Fernando, R., et al., <i>Adaptive Shadow Maps</i> , Proceedings of ACM SIGGRAPH 2001, August 2001, pp 387-390
		Govindaraju, N., et al., <i>Interactive Shadow Generation in Complex Environments</i> , Proceedings of SIGGRAPH 2003, pp 501-510
		Lokovic, T., et al., <i>Deep Shadow Maps</i> , Proceedings of SIGGRAPH 2000, pp 385-392
		Stamminger, M., et al., <i>Perspective Shadow Maps</i> , Proceedings of SIGGRAPH 2002, Vol. 21, No. 3, pp 557-562

EXAMINER SIGNATURE	DATE CONSIDERED
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.pto.gov or MPEP 901.4. ³ Enter Office that issued the document, by the two-letter code (WIPO standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English Language Translation is attached.	

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OTHER DOCUMENTS		
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		Tadamura, K., et al., <i>Rendering Optimal Solar Shadows Using Plural Sunlight Depth Buffers</i> , The Visual Computer, Vol. 17, No. 2, 2001, pp 1-8
		Woo, A., et al., <i>A Survey of Shadow Algorithms</i> , IEEE Computer Graphics and Applications, Vol. 10, No. 6, November 1990, pp 13-32
		Williams, L., <i>Casting Curved Shadows on Curved Surfaces</i> , Proceedings of SIGGRAPH 1978, Vol. 12, No. 3, pp 270-274
		Crow, F., <i>Shadow Algorithms For Computer Graphics</i> , Proceedings of SIGGRAPH 1977, pp 242-248
		Kozlov, S., <i>Perspective Shadow Maps: Care and Feeding</i> , GPU Gems: Programming Techniques, Tips and Tricks for Real-Time Graphics, 2004, Chapter 14, pp. 217-244
		Low, K., et al., <i>View Frustum Optimization To Maximize Object's Image Area</i> , Technical Report TR02-024, Department of Computer Science, University of North Carolina, May 2002, pp 1-7
		Segal, M., et al., <i>Fast Shadows and Lighting Effects Using Texture Mapping</i> , Computer Graphics, Vol. 26, No. 2, July 1992, pp 249-252
		Sen, P., et al., <i>Shadow Silhouette Maps</i> , Proceedings of SIGGRAPH 2003, pp 521-526
		Wang, Y., et al., <i>Second-Depth Shadow Mapping</i> , Technical Report TR94-019, Department of Computer Science, University of North Carolina, 1994, pp 1-8

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